



RELIABILITY REPORT
FOR
MAX15046BAEE+T
PLASTIC ENCAPSULATED DEVICES

December 10, 2010

MAXIM INTEGRATED PRODUCTS

120 SAN GABRIEL DR.
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Conclusion

The MAX15046BAEE+T successfully meets the quality and reliability standards required of all Maxim products. In addition, Maxim's continuous reliability monitoring program ensures that all outgoing product will continue to meet Maxim's quality and reliability standards.

Table of Contents

I.Device Description	V.Quality Assurance Information
II.Manufacturing Information	VI.Reliability Evaluation
III.Packaging Information	IV.Die Information
.....Attachments	

I. Device Description

A. General

The MAX15046 synchronous step-down controller operates from a 4.5V to 40V input voltage range and generates an adjustable output voltage from 85% of the input voltage down to 0.6V, supporting loads up to 25A. The device allows monotonic startup into a prebiased bus without discharging the output and features adaptive internal digital soft-start. The MAX15046 offers the ability to adjust the switching frequency from 100kHz to 1MHz with an external resistor. The MAX15046's adaptive synchronous rectification eliminates the need for an external freewheeling Schottky diode. The device also utilizes the external low-side MOSFET's on-resistance as a current-sense element, eliminating the need for a current-sense resistor. This protects the DC-DC components from damage during output overloaded conditions or output short-circuit faults without requiring a current-sense resistor. Hiccup-mode current limit reduces power dissipation during short-circuit conditions. The MAX15046 includes a power-good output and an enable input with precise turn-on/turn-off threshold, which can be used for input supply monitoring and for power sequencing. Additional protection features include sink-mode current limit, and thermal shutdown. Sink-mode current limit prevents reverse inductor current from reaching dangerous levels when the device is sinking current from the output. The MAX15046 is available in a 16-pin QSOP or 16-pin QSOP-EP package and operates over the -40°C to +125°C temperature range.

II. Manufacturing Information

A. Description/Function:	40V, High-Performance, Synchronous Buck Controller
B. Process:	S45
C. Number of Device Transistors:	516
D. Fabrication Location:	California, Texas or Japan
E. Assembly Location:	Thailand and Philippines
F. Date of Initial Production:	July 25, 2009

III. Packaging Information

A. Package Type:	16-pin QSOP
B. Lead Frame:	Copper
C. Lead Finish:	100% matte Tin
D. Die Attach:	Conductive
E. Bondwire:	Au (1.3 mil dia.)
F. Mold Material:	Epoxy with silica filler
G. Assembly Diagram:	#05-9000-3570
H. Flammability Rating:	Class UL94-V0
I. Classification of Moisture Sensitivity per JEDEC standard J-STD-020-C	Level 1
J. Single Layer Theta Ja:	120°C/W
K. Single Layer Theta Jc:	37°C/W
L. Multi Layer Theta Ja:	103.7°C/W
M. Multi Layer Theta Jc:	37°C/W

IV. Die Information

A. Dimensions:	66 X 76 mils
B. Passivation:	Si ₃ N ₄ /SiO ₂ (Silicon nitride/ Silicon dioxide)
C. Interconnect:	Al/0.5%Cu with Ti/TiN Barrier
D. Backside Metallization:	None
E. Minimum Metal Width:	Metal1 = 0.5 / Metal2 = 0.6 / Metal3 = 0.6 microns (as drawn)
F. Minimum Metal Spacing:	Metal1 = 0.45 / Metal2 = 0.5 / Metal3 = 0.6 microns (as drawn)
G. Bondpad Dimensions:	5 mil. Sq.
H. Isolation Dielectric:	SiO ₂
I. Die Separation Method:	Wafer Saw

V. Quality Assurance Information

A. Quality Assurance Contacts:	Richard Aburano (Manager, Reliability Operations) Bryan Preeshl (Vice President of QA)
B. Outgoing Inspection Level:	0.1% for all electrical parameters guaranteed by the Datasheet. 0.1% For all Visual Defects.
C. Observed Outgoing Defect Rate:	< 50 ppm
D. Sampling Plan:	Mil-Std-105D

VI. Reliability Evaluation

A. Accelerated Life Test

The results of the 135°C biased (static) life test are shown in Table 1. Using these results, the Failure Rate (λ) is calculated as follows:

$$\lambda = \frac{1}{\text{MTTF}} = \frac{1.83}{192 \times 4340 \times 48 \times 2} \quad (\text{Chi square value for MTTF upper limit})$$

(where 4340 = Temperature Acceleration factor assuming an activation energy of 0.8eV)

$$\lambda = 22.9 \times 10^{-9}$$
$$\lambda = 22.9 \text{ F.I.T. (60\% confidence level @ 25°C)}$$

The following failure rate represents data collected from Maxim's reliability monitor program. Maxim performs quarterly life test monitors on its processes. This data is published in the Reliability Report found at <http://www.maxim-ic.com/qa/reliability/monitor>. Cumulative monitor data for the S45 Process results in a FIT Rate of 0.49 @ 25C and 8.49 @ 55C (0.8 eV, 60% UCL)

B. E.S.D. and Latch-Up Testing (lot SUGZBQ001B, D/C 0916/0929)

The NQ42 die type has been found to have all pins able to withstand a HBM transient pulse of +/- 2500V per JEDEC JESD22-A114. Latch-Up testing has shown that this device withstands a current of +/- 100mA and overvoltage per JEDEC JESD78.

Table 1
Reliability Evaluation Test Results

MAX15046BAEE+T

TEST ITEM	TEST CONDITION	FAILURE IDENTIFICATION	SAMPLE SIZE	NUMBER OF FAILURES	COMMENTS
Static Life Test (Note 1)	Ta = 135°C Biased Time = 192 hrs.	DC Parameters & functionality	48	0	SUGZBQ001B, D/C 0916

Note 1: Life Test Data may represent plastic DIP qualification lots.